HORIBA Scientific

Designed for use in the NIR, applications include NIR Raman, photoluminescence, emission, and absorbance spectroscopy.

Symphony II
Linear InGaAs Array
SII-1LS-512-25-17
SII-1LS-1024-25-17

FLUORESCENCE

GRATINGS & OEM SPECTROMETERS

OPTICAL COMPONENTS

FORENSICS

PARTICLE CHARACTERIZATION

RAMAN

SPECTROSCOPIC ELLIPSOMETRY

SPR IMAGING

HORIBA Scientific's Symphony II InGaAs arrays are the ideal choice for demanding, low-light-level measurements in the near infrared (NIR) spectral region from 800-1700 nm. Offered in 512×1 (25×500 µm), 512×1 (50×500 µm), and 1024×1 (25×500 µm) pixel formats, these InGaAs detectors provide high resolution while maintaining full well capacity. Symphony II InGaAs arrays feature a 16-bit dynamic range, are liquid-nitrogen cooled to minimize dark noise, and use a mechanical shutter for subtraction of the dark background. Available with a 3-liter dewar for hours of uninterrupted data-collection. A plug-and-play USB 2.0 interface allows portability and easy setup on PC notebooks and desktop computers with 100% data integrity. Applications include near-IR Raman, photoluminescence measurements of semiconductors, SWCNTs, and nanowires. Detectors with sensitivity from 1 µm to 2.2 µm are also available.



Feature	Spectroscopy Benefits		
Cryogenic Cooling	Cools the array to –103°C to minimize dark noise		
Excellent Linearity	High accuracy of data over the full dynamic range		
USB 2.0 Interface	Easy to use; connects to PC notebooks and desktops with 100% data integrity		
High Sensitivity (HiS) and High Dynamic Range (HiD) modes	Software selection of acquisition mode to optimize detector for best signal-to- noise ratio		
Auxiliary Signal Input	Unique ability to add measurements from single-channel detectors without additional electronics		
HORIBA Scientific's SynerJY® Software	Complete control of a Symphony II CCD and HORIBA Scientific Spectrograph system with full analysis capabilities		
LabVIEW VIs and SDK Available	Flexible software to integrate a Symphony II CCD into existing apparatus or as an OEM component JOBIN YVON Technology		



ELEMENTAL ANALYSIS

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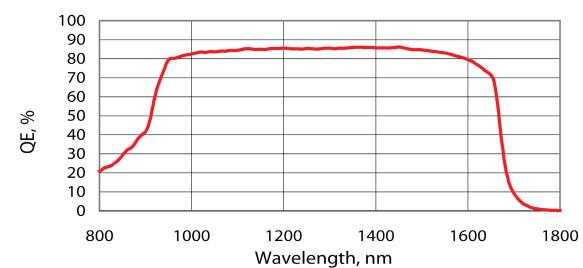
RAMAN
SPECTROSCOPIC ELLIPSOMETRY
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Specifications*

Format		512 × 1	512 × 1	1024 × 1		
		(25 × 500)	(50 × 500)	(25 × 500)		
Wavelength	avelength Ambient Temp. (25°C)		800–1 <i>7</i> 00 nm			
Range	Operating Temp. (-103°C)	800-1600 nm				
Operating Temperature (Typical)		–103°C				
9 9 9			Typical			
Readout	HiS Mode (High Gain)	0.5–0.8 ke ⁻ rms				
Noise	HiD Mode (Low Gain)	5–7 ke ⁻ rms				
Full Well	HiS Mode (High Gain)	5 Me⁻				
Capacity	HiD Mode (Low Gain)	130 Me⁻				
Dark Current		3 ke ⁻ /p/s	7 ke ⁻ /p/s	4 ke ⁻ /p/s		
Response Nonuniformity		± 10%	± 5%	± 10%		
Response Nonlinearity		< ± 1%				
Gaio (Namical) HiS Mode (High Gain)		58 e⁻/count				
Gain (Nominal)	HiD Mode (Low Gain)	1 <i>5</i> 45 e ⁻ /count				
Dynamic Range		16 bit				
Pixel Defects		Max of 5 dark or hot pixels	Max of 5 dark or hot pixels	Max of 10 dark or hot pixels		

*Specifications subject to change without notice.

Quantum Efficiency at 25 °C



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